FORM PTO 1449 (modilied)			ATTY DOCKET NO. APPLICATION NO. 03500.015727. 09/941,780				
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^{*}EXAMINER: Initial il reference considered, whether or not clistion is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant.

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	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	APPLICANT							
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